公TDK

SPECIFICATION

SPEC. No.

C2011-1380

DATE:

Sep. 26, 2011

SOSHARE

CUSTOMER'S PRODUCT NAME

TDK PRODUCT NAME
MULTILAYER CERAMIC CHIP CAPACITORS
C3225X5R1E226K

Please return this specification to TDK representatives. If orders are placed without returned specification, please allow us to judge that specification is accepted by your side.

THIS SPECIFICATION IS RECEIVED

DATE:

YEAR

MONTH

DAY

TDK-EPC Corporation 1-13-1, Nihonbashi, Chuo-ku, Tokyo 103-0027. Japan

ENGINEERING
LSSUED

1SSUED
CHECKED

APPROVED

N. Yanagiliashi T. Umuma

DATE

Sep. 26. 201 | DATE Sep. 28. 201 | DATE Sep. 28. 201 |

Sales Office

Sales Tel. (

PRODUCT CLASSIFICATION CODE

040320

1. SCOPE

This specification is applicable to chip type multilayer ceramic capacitors with a priority over the other relevant specifications.

Production places defined in this specification shall be TDK-EPC Corporation,

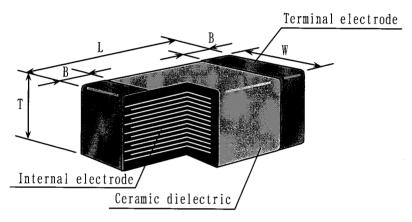
EXPLANATORY NOTE:

This specification warrants the quality of the ceramic chip capacitor. The chips should be evaluated or confirmed a state of mounted on your product. If the use of the chips go beyond the bounds of the specification, we can not afford to guarantee.

2. CODE CONSTRUCTION

<u> C3225</u>	<u>X5R</u>	<u>1 E</u>	$_{226}$	<u>K</u>	<u>T</u>
(1)	(2)	(3)	(4)	(5)	(6)

(1) Type



Type	Dimensions (Unit : mm)				Dimensions	
TDK (EIA style)	L	W	T	В		
C3225 (CC1210)	3.20 ± 0.40	2.50 ± 0.30	2.50 ± 0.30	0.20 min.		

(2) Temperature Characteristics (Details are shown in para. 9 No. 6)

(3) Rated Voltage

Symbol	Rated Voltage
1 E	DC 25 V

(4) Rated Capacitance

Stated in three digits and in units of pico farads (pF). The first and Second digits identify the first and second significant figures of the Capacitance, the third digit identifies the multiplier.

 $226 \rightarrow 22,000,000 pF$



(5) Capacitance tolerance

Symbol	Tolerance
K	± 10 %

(6) Packaging

Symbol	Packaging
В	Bulk
T	Taping

3. OPERATING TEMPERATURE RANGE

Min. operating	Max. operating	Reference
Temperature	Temperature	Temperature
-55℃	85℃	25℃

4. STORING CONDITION AND TERM

5 to 40°C at 20 to 70%RH

6 months Max.

5. P. C. BOARD

This specification not applicable to Aluminum or some other substrate for such application, please state so and inquire separate specification.

6. RECOMMENDATION

It is recommended to provide a slit (about 1mm) on the board under the components to improve washing Flux.

And please make sure to dry detergent up completely before.

7. SOLDERING CONDITION

Reflow soldering only.

8. INDUSTRIAL WASTE DISPOSAL

Dispose this product as industrial waste in accordance with the industrial Waste Law.



9. PERFORMANCE

table 1

	T	table 1	· · · · · · · · · · · · · · · · · · ·		
No.	Item	Performance	Test or inspection method		
1	External Appearance	No defects which may affect performance.	Inspect with magnifying glass(3×)		
2	Insulation Resistance	4.5 MΩ min.	Apply rated voltage for 60s.		
3	Voltage Proof	Withstand test voltage without insulation breakdown or other damage.	2.5 times of rated voltage Above DC voltage shall be applied for 1~5s. Charge / discharge current shall not exceed 50mA.		
4	Capacitance	Within the specified tolerance.			
			Measuring frequency Measuring voltage		
			120Hz ± 20% 0.5 ± 0.2V rms.		
	Dissipation Factor	Characteristics			
		T. C. Rated Voltage D. F.	Measuring Measuring frequency voltage		
		X5R 25V DC 0. 05 max.	120Hz ± 20% 0.5±0.2V rms.		
6	Temperature Characteristics of Capacitance	Capacitance Change (%) No voltage applied X5R : ±15	Capacitance shall be measured by the steps shown in the following table, after thermal equilibrium is obtained for each step. △C be calculated ref. STEP3 reading. Step Temperature (℃) 1 25 ± 2 2 -55 ± 2 3 25 ± 2 4 85 ± 2		
7	Robustness of Terminations	No sign of termination coming off, breakage of ceramic, or other abnormal signs.	Reflow solder the capacitor on a P. C. Board shown in Appendix2 and apply a pushing force of 5N for $10\pm1s$.		

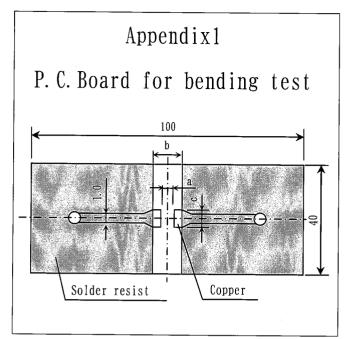
	inued)		T			
No.		tem		formance	Test or inspection method	
8	Bending		No mechanica	l damage.	Reflow solder the capacitor on a P.C. Board shown in Appendix 1 and Bend it for 1mm. The solution of the capacitor on a P.C. Board shown in Appendix 1 and Bend it for 1mm. The solution of the capacitor on a P.C. Board shown in Appendix 1 and Bend it for 1mm.	
9	Solderabil	ity	New solder to cover over 75% of termination. 25% may have pin holes or rough spots but not concentrated in one spot. Ceramic surface of A sections shall not be exposed due to melting or shifting of termination material. A section		Completely soak both terminations is solder at 235±5℃ for 2±0.5s. Solder: H63A(JIS Z 3282)	
10	Resistance to solder heat	External appearance Capacitance D. F. Insulation Resistance Voltage proof External	No cracks are terminations at least 60% Characteristics X5R Meet the init No insulatio other damage. No mechanical	callowed and shall be covered with new solder. Change from the value before test ±7.5 % ial spec. ial spec. n breakdown or	Completely soak both terminations in solder at 260±5°C for 5±1s. Preheating condition Temp.: 150±10°C Time: 1~2min. Flux: Isopropyl alcohol (JIS K 8839) Rosin (JIS K 5902) 25% solid solution. Solder: H63A (JIS Z 3282) Leave the capacitors in ambient condition for 48±4h before measurement.	
	vibration	External appearance Capacitance	No mechanical Characteristics X5R	Change from the value before test $\pm 7.5 \%$	Reflow Solder the capacitors on a P. C. Board shown in Appendix2 before testing. Vibrate the capacitor with amplitude of 1.5mm P-P changing the frequencies from 10Hz to 55Hz and back to 10Hz in about 1min. Repeat this for 2h each in 3 perpendicular directions.	
		D. F.	Meet the init	ial spec.		

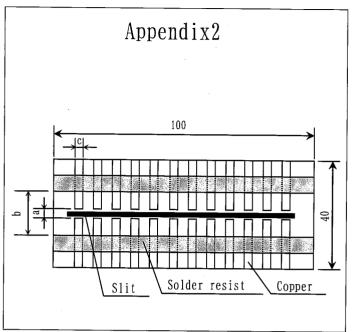
No.	tinued) I	Item Performan		Test or inspection method		
12	Temperature cycle	External appearance	No mechanical damage.	Reflow Solder the capacitors on a P. C. Board shown in Appendix2 before		
		Capacitance	Characteristics Change from the value before test X5R ± 12.5 %	testing. Expose the capacitors in the condition step1 through 4 and repeat 5 times consecutively. Leave the capacitors in ambient condition for 48±4h before		
		D. F.	Meet the initial spec.	measurement. Step Temperature (°C) Time (min.)		
		Insulation Resistance	Meet the initial spec.	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$		
		Voltage proof	No insulation breakdown or	2 Reference Temp. 2~5		
		proor	other damage.	$\frac{3}{85 \pm 2} \frac{30 \pm 2}{30 \pm 2}$		
				4 Reference Temp. 2~5		
13	Moisture Resistance	External appearance	No mechanical damage.	Reflow Solder the capacitors on a P. C. Board shown in Appendix2 before		
	(Steady State)	Capacitance	Characteristics Change from the value before test X5R ± 25 %	testing. Leave at temperature $40\pm2\%$, 90 to 95%RH for 500 +24, 0h. Leave the capacitors in ambient condition for 48 ± 4 h before		
		D. F.	characteristics X5R: 200% of initial spec max.	measurement.		
		Insulation Resistance	0.4 MΩ min.			
4	Moisture Resistance	External appearance	No mechanical damage.	Reflow Solder the capacitors on a P.C. Board shown in Appendix2 before testing.		
		Capacitance	Characteristics Change from the value before test X5R ± 25 %	Apply the rated voltage at temperature 40±2°C and 90 to 95%RH for 500 +24, 0h. Charge/discharge current shall not		
		D. F.	characteristics X5R : 200% of initial spec max.	exceed 50mA. Leave the capacitors in ambient condition for 48±4h before		
		Insulation Resistance	0.2 MΩ min.	woltage conditioning Voltage treat the capacitor under testing temperature and voltage for lhour. Leave the capacitors in ambient condition for 48 ± 4h before measurement. Use this measurement for initial value.		

(continued)

No.	I t	em	Perfo	ormance	Test or inspection method
15	Life	External appearance	No mechanical	damage.	Reflow Solder the capacitors on a P. C. Board shown in Appendix2 before
		Capacitance	Characteristics	Change from the value before test	- testing. Apply rated voltage at 85±2℃ for 1,000 +48,0h.
	X5R ± 25 %		± 25 %	Charge/discharge current shall not exceed 50mA.	
		D. F.	characteristic X5R: 200% of in		Leave the capacitors in ambient condition for 48±4h before measurement.
		Insulation Resistance	0.4 MΩ min.		Voltage conditioning Voltage treat the capacitor under testing temperature and voltage for 1hour. Leave the capacitors in ambient condition for 48 ± 4h before measurement. Use this measurement for initial value.

^{*}As for the initial measurement of capacitors on number 6, 10, 11, 12 and 13, leave capacitors at 150 -10,0°C for 1h and measure the value after leaving capacitors for 48±4h in ambient condition.





(Unit:mm)

Type	Dimensions		
TDK (EIA style) a		b	С
C3225 (CC1210)	2. 2	5. 0	2. 9

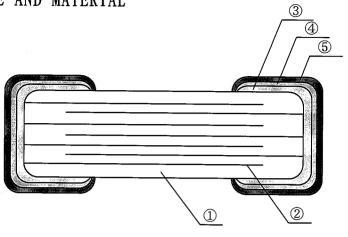
1. Material : Glass Epoxy (As per JIS C6484 GE4)

2. Thickness: 1.6mm

Copper (Thickness: 0.035mm)

Solder resist

INSIDE STRUCTURE AND MATERIAL



No.	NAME	MATERIAL
1	Dielectric	BaTiO ₃
2	Electrode	Ni
3		Cu
4	Termination	Ni
⑤		Sn

PACKAGING

Packaging shall be done to protect the components from the damage during transportation and storing, and a label which has the following information shall be attached.

- 1) Total number of components in a plastic bag for bulk packaging : 1000pcs
- 2) Tape packaging is as per TDK tape packaging specification.

Information on label

- 1) Inspection No.
- 2) TDK P/N
- 3) Customer's P/N
- 4) Quantity

*Composition of Inspection No.

Example
$$\frac{M}{(a)} \frac{1}{(b)} \frac{A}{(c)} - \frac{\bigcirc\bigcirc}{(d)} - \frac{\bigcirc\bigcirc}{(e)}$$

- a) Line code
- b) Last digit of the year
- c) Month and A for January and B for February and so on. (Skip I)
- d) Inspection Date of the month.
- e) Serial No. of the day

Caution

<u>Cau</u> t	ion	
No.	Process	Condition
1	Operating Condition (Storage, Transportation)	 1-1. Storage 1) The capacitors must be stored in an ambient temperature of 5 to 40℃ with a relative humidity of 20 to 70%RH. The products should be used within 6 months upon receipt.
		2) The capacitors must be operated and stored in an environment free of dew condensation and these gases such as Hydrogen Sulphide, Hydrogen Sulphate, Chlorine, Ammonia and sulfur.
		3) Avoid storing in sun light and falling of dew.
		4) Do not use capacitors under high humidity and high and low atmospheric pressure which may affect capacitors reliability.
		5) Capacitors should be tested for the solderability when they are stored for long time.
		1-2. Handling in transportation In case of the transportation of the capacitors, the performance of the capacitors may be deteriorated depending on the transportation condition. (Refer to JEITA RCR-2335B 9.2 Handling in transportation)
2	Circuit design Caution	2-1. Operating temperature Operating temperature should be followed strictly within this specification, especially be careful with maximum temperature.
		1) Do not use capacitors above the maximum allowable operating temperature.
2) Surface temperature including self heating should be belo temperature. (Due to dielectric loss, capacitors will heat itself we Especially at high frequencies around its SRF, the heat it that it may damage itself or the product mounted on. Please so that the maximum temperature of the capacitors including to be below the maximum allowable operating temperature.		
		3) The electrical characteristics of the capacitors will vary depending on the temperature. The capacitors should be selected and designed in taking the temperature into consideration.
		 2-2. Operating voltage 1) Operating voltage across the terminals should be below the rated voltage. When AC and DC are super imposed, V_{0-P} must be below the rated voltage.
		AC or pulse with overshooting, V_{P-P} must be below the rated voltage.
	When the voltage is started to apply to the circuit or it is store the irregular voltage may be generated for a transit period resonance or switching. Be sure to use the capacitors within containing these Irregular voltage.	
		Voltage (1) DC voltage (2) DC+AC voltage (3) AC voltage
		Positional Measurement (Rated voltage) V_{0-P} 0 V_{0-P}
		Voltage (4) Pulse voltage (A) (5) Pulse voltage (B)
		Positional Measurement (Rated voltage) V_{P-P}

No.	Process	Condition
2	Circuit design Caution	Condition 2) Even below the rated voltage, if repetitive high frequency AC or pulse is applied, the reliability of the capacitors may be reduced.
		3) The effective capacitance will vary depending on applied DC and AC voltages. The capacitors should be selected and designed in taking the voltages into consideration.
		2-3. Frequency When the capacitors (Class 2) are used in AC and/or pulse voltages, the capacitors may vibrate themselves and generate audible sound.
3	Designing P. C. board	The amount of solder at the terminations has a direct effect on the reliability of the capacitors.
		1) The greater the amount of solder, the higher the stress on the chip capacitors, and the more likely that it will break. When designing a P.C. board, determine the shape and size of the solder lands to have proper amount of solder on the terminations.
		2) Avoid using common solder land for multiple terminations and provide individual solder land for each terminations.
		3) Size and recommended land dimensions.
		Chip capacitors Solder land
		Solder resist
		Reflow soldering
		Type C3225 (CC1210) A 2. 0 ~ 2. 4
		B 1.0 ~ 1.2
		C 1.9 ∼ 2.5

Vo.	Process			Condition	
3	Designing P.C.board	4)	Recommended o	chip capacitors layout is as f	Collowing.
				Disadvantage against bending stress	Advantage against bending stress
			Mounting face	Perforation or slit	Perforation or slit
				Break P.C. board with mounted side up.	Break P.C. board with mounted side down.
			Chip arrangement (Direction)	Mount perpendicularly to perforation or slit Perforation or slit	Mount in parallel with perforation or slit Perforation or slit
			Distance from slit	Closer to slit is higher stress	Away from slit is less stress
				$(\mathcal{L}_1 < \mathcal{L}_2)$	$(\mathcal{L}_1 \langle \mathcal{L}_2)$

No. Process

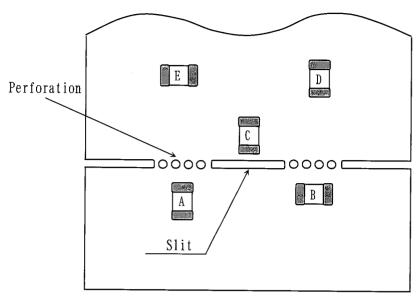
Condition

Besigning P. C. board

Condition

Condition

Solution of this capacitors on the P. C. board.



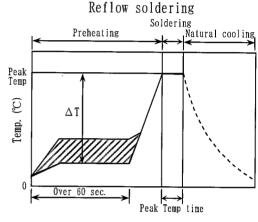
The stress in capacitors is in the following order. A > B = C > D > E

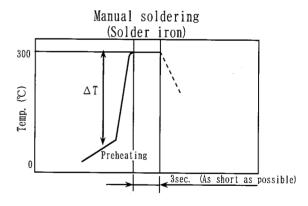
6) Layout recommendation

Example Use of common solder land		Soldering with chassis	Use of common solder land with other SMD	
Need to avoid	Lead wire Chip Solder PCB Solder land	Chassis Excessive solder	Solder land Excessive solder Missing solder land	
Recommen- dation	Solder resist	Solder resist $\ell^2 > \ell^1$	Solder resist	

No.	Process		Condition	
4	Mounting	the chip capaci 1) Adjust the bosurface and p 2) Adjust the mosurface and p	s head is adjusted too low, it tors to result in cracking. Ple ttom dead center of the mountin not press it. Dounting head pressure to be 1 the impact energy from mounting I the bottom side of the P.C. bot	head, it is important to provide
			Not recommended	Recommended
		Single sided mounting	Crack	Support pin
		Double-sides mounting	Solder peeling Crack	Support pin
		to cause crack. Pl	jaw is worn out, it may give mech lease control the close up dime t preventive maintenance and r	nsion of the centering jaw and

No.	Process	Condition
5	Soldering	5-1. Flux selection Although highly-activated flux gives better solderability, substances which increase activity may also degrade the insulation of the chip capacitors. To avoid such degradation, it is recommended following.
		1) It is recommended to use a mildly activated rosin flux (less than 0.1wt% chlorine). Strong flux is not recommended.
		2) Excessive flux must be avoided. Please provide proper amount of flux.
		3) When water-soluble flux is used, enough washing is necessary.
		5-2. Recommended soldering profile by various methods
		Reflow soldering





5-3. Recommended soldering peak temp and peak temp duration

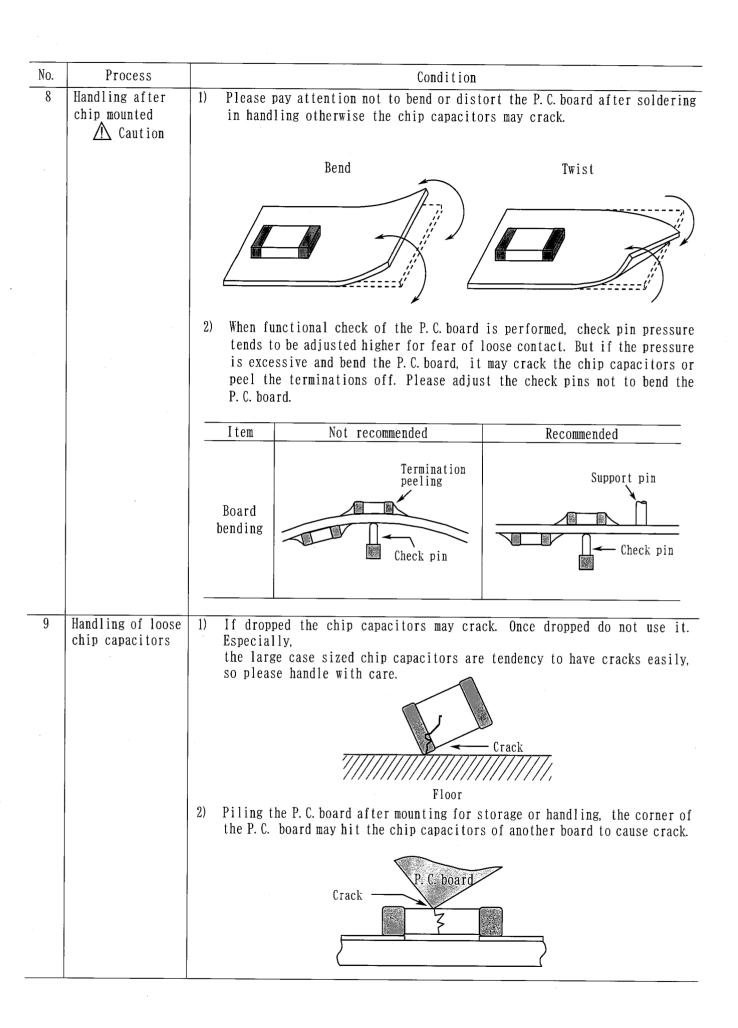
Temp./Duration	Reflow soldering		
Solder	Peak temp(℃)	Duration (sec.)	
Sn-Pb Solder	230 max.	20 max.	
Lead Free Solder	260 max.	10 max.	

Recommended solder compositions Sn-37Pb (Sn-Pb solder) Sn-3.0Ag-0.5Cu (Lead Free Solder)



No.	Process	Condition
5	Soldering	5-4. Avoiding thermal shock
		1) Preheating condition
		Soldering Temp. (°C)
		$\frac{\text{Reflow soldering}}{\text{Reflow soldering}} \Delta T \leq 130$
		$\frac{\text{Manual soldering}}{\text{Manual soldering}} \Delta T \leq 130$
		$\frac{\text{Manual Solutions}}{\Delta 1} \triangleq 150$
		2) Cooling condition Natural cooling using air is recommended. If the chips are dipped into a solvent for cleaning, the temperature difference (ΔT) must be less than 100°C.
,		5-5. Amount of solder
		Excessive solder will induce higher tensile force in chip capacitors when temperature changes and it may result in chip cracking. In sufficient solder may detach the capacitors from the P.C. board.
		Excessive solder Higher tensile force in chip capacitors to cause crack
		Adequate Maximum amount Minimum amount
		Insufficient solder Low robustness may cause contact failure or chip capacitors come off the P. C. board.
		5-6. Solder repair by solder iron 1) Selection of the soldering iron tip Tip temperature of solder iron varies by its type, P. C. board material and solder land size. The higher the tip temperature, the quicker the operation. However, heat shock may cause a crack in the chip capacitors. Please make sure the tip temp. before soldering and keep the peak temp and time in accordance with following recommended condition. (Please preheat the chip capacitors with the condition in 5-4 to avoid the thermal shock.)
		Recommended solder iron condition (Sn-Pb Solder and Lead Free Solder)
		Temp. (°C) Duration (sec.) Wattage (W) Shape (mm)
		300 max. 3 max. 20 max. φ 3. 0 max.
		Ψ 0. 0 шαλ.
		2) Direct contact of the soldering iron with ceramic dielectric of chip capacitors may cause crack. Do not touch the ceramic dielectric and the terminations by solder iron.

No.	Process	Condition
5	Soldering	5-7. Sn-Zn solder Sn-Zn solder affects product reliability. Please contact TDK in advance when utilize Sn-Zn solder. 5-8. Countermeasure for tombstone The misalignment between the mounted positions of the capacitors and the land patterns should be minimized. The tombstone phenomenon may occur especially the capacitors are mounted (in longitudinal direction) in the same direction of the reflow soldering. (Refer to JEITA RCR-2335B Annex A (Informative) Recommendations to prevent the tombstone phenomenon)
(Refer to JEITA RCR-2335B Annex tombstone phenomenon) 1) If an unsuitable cleaning flu may stick to chip capacitors a resistance. 2) If cleaning condition is not 2)-1. Insufficient washing (1) Terminal electrodes may (2) Halogen in the flux may a the insulation resistance (3) Water soluble flux has hi (1) and (2). 2)-2. Excessive washing When ultrasonic cleaning is can affect the connection be terminal electrode. To avoi Power: 20W/& max. Frequency: 40kHz max.		may stick to chip capacitors surface to deteriorate especially the insulation resistance. 2) If cleaning condition is not suitable, it may damage the chip capacitors. 2)-1. Insufficient washing (1) Terminal electrodes may corrode by Halogen in the flux. (2) Halogen in the flux may adhere on the surface of capacitors, and lower the insulation resistance. (3) Water soluble flux has higher tendency to have above mentioned problems (1) and (2). 2)-2. Excessive washing When ultrasonic cleaning is used, excessively high ultrasonic energy output can affect the connection between the ceramic chip capacitor's body and the terminal electrode. To avoid this, following is the recommended condition.
7	Coating and molding of the P.C. board	 When the P.C. board is coated, please verify the quality influence on the product. Please verify carefully that there is no harmful decomposing or reaction gas emission during curing which may damage the chip capacitors.
		3) Please verify the curing temperature.

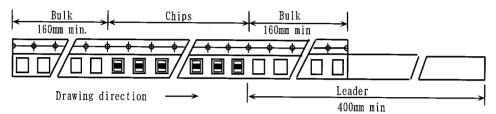


No.	Process	Condition		
10	Capacitance aging	The capacitors (Class 2) have aging in the capacitance. They may not be used in precision time constant circuit. In case of the time constant circuit, the evaluation should be done well.		
11	Estimated life and estimated failure rate of capacitors	As per the estimated life and the estimated failure rate depend on the temperature and the voltage. This can be calculated by the equation described in JEITA RCR-2335B Annex 6 (Informative) Calculation of the estimated lifetime and the estimated failure rate (Voltage acceleration coefficient: 3 multiplication rule, Temperature acceleration coefficient: 10°C rule) The failure rate can be decreased by reducing the temperature and the voltage but they will not be guaranteed.		
12 Others Caution The products listed on this specification sheet are intended for electronic equipment (AV equipment, telecommunications equipment appliances, amusement equipment, computer equipment, personal equ		The products listed on this specification sheet are intended for use in general electronic equipment (AV equipment, telecommunications equipment, home appliances, amusement equipment, computer equipment, personal equipment, office equipment, measurement equipment, industrial robots) under a normal operation and use condition.		
		The products are not designed or warranted to meet the requirements of the applications listed below, whose performance and/or quality require a more stringent level of safety or reliability, or whose failure, malfunction or trouble could cause serious damage to society, person or property. Please understand that we are not responsible for any damage or liability caused by use of the products in any of the applications below or for any other use exceeding the range or conditions set forth in this specification sheet. If you intend to use the products in the applications listed below or if you have special requirements exceeding the range or conditions set forth in this specification, please contact us.		
		 Aerospace/Aviation equipment Transportation equipment (cars, electric trains, ships, etc.) Medical equipment Power-generation control equipment Atomic energy-related equipment Seabed equipment Transportation control equipment Public information-processing equipment Military equipment Electric heating apparatus, burning equipment Disaster prevention/crime prevention equipment Safety equipment Other applications that are not considered general-purpose applications 		
		When designing your equipment even for general-purpose applications, you are kindly requested to take into consideration securing protection circuit/device or providing backup circuits in your equipment.		

TAPE PACKAGING SPECIFICATION

1. CONSTRUCTION AND DIMENSION OF TAPING

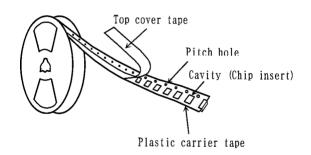
- 1-1. Dimensions of carrier tape Dimensions of plastic tape shall be according to Appendix 3.
- 1-2. Bulk part and leader of taping



1-3. Dimensions of reel

Dimensions of ϕ 178 reel shall be according to Appendix 4. Dimensions of ϕ 330 reel shall be according to Appendix 5.

1-4. Structure of taping

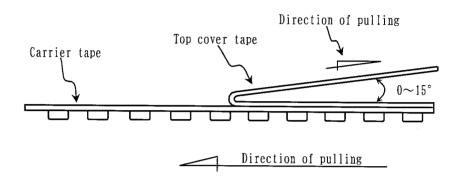


2. CHIP QUANTITY

Туре	Thickness	Taping Material	Chip quantity(pcs.)	
1 y p c	of chip		φ178mm reel	φ330mm reel
C3225	2.50 mm	plastic	1, 000	5, 000

3. PERFORMANCE SPECIFICATIONS

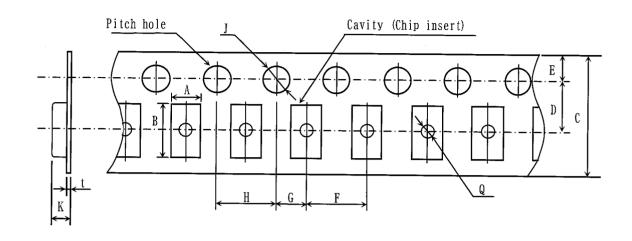
3-1. Fixing peeling strength (top tape) 0.05-0.7N. (See the following figure.)



- 3-2. Carrier tape shall be flexible enough to be wound around a minimum radius of 30mm with components in tape.
- 3-3. The missing of components shall be less than 0.1%
- 3-4. Components shall not stick to fixing tape.
- 3-5. The fixing tapes shall not protrude beyond the edges of the carrier tape nor shall cover the sprocket holes.

Appendix 3

<u>Plastic Tape</u>



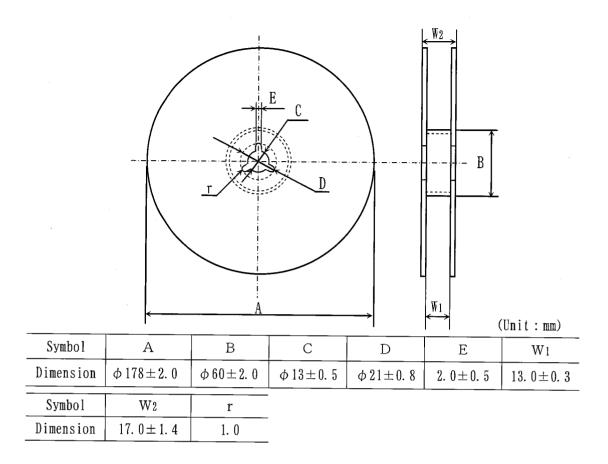
(Unit	:	mm)
-------	---	-----

Symbol Type	А	В	С	D	Е	F
C3225	* (2. 9)	* (3. 6)	12. 0±0. 3	5. 5±0. 05	1. 75±0. 1	4. 0±0. 1

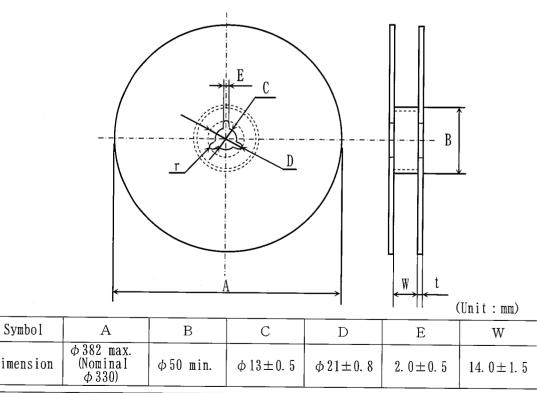
Symbol Type	G	Н	J	K	t	Q
C3225	2.0 ± 0.05	4.0 ± 0.1	ϕ 1. 5 $\begin{array}{c} +0.1 \\ 0 \end{array}$	3. 2 max.	0.6 max.	φ0.5 min.

* Referenced value

Appendix 4 (Reel material: Polystyrene)



Appendix 5 (Reel material: Polystyrene)



	Dimension	(Nominal φ330)	φ50 min.	$\phi 13 \pm 0.5$	$\phi 21 \pm 0.8$	2.0 ± 0.5	14. 0 ± 1 . 5
	Symbol	t	r				
_	Dimension	2.0 ± 0.5	1. 0				